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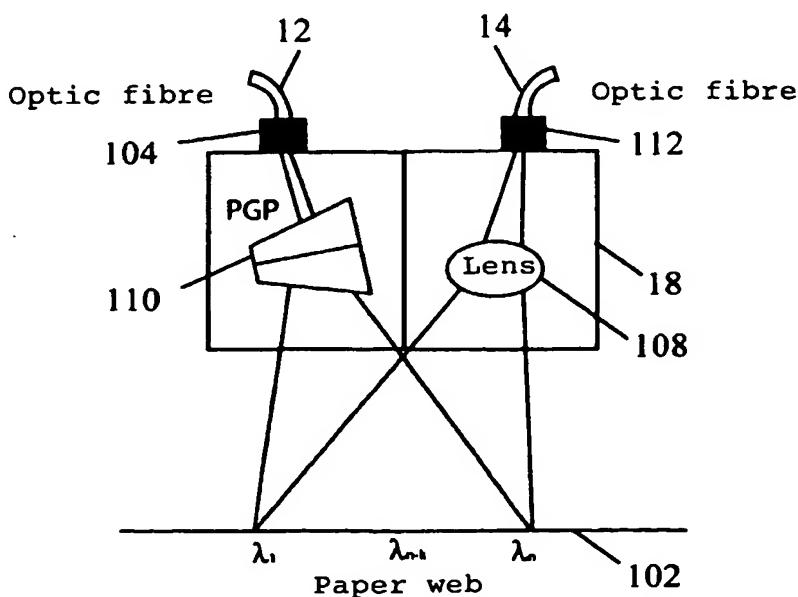
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(54) Title: DETECTION OF A DEVIATION IN A MATERIAL USING A SPECTRAL CAMERA



(57) Abstract: A method for coding a place in an analyzable material according to a wavelength. In a method according to the invention the light produced by the light source is dispersed as several spectrums to the surface of an analyzable moving planar material, the spectrums reflected from the surface of the analyzable moving planar material are collected, the collected spectrums are guided into a spectrum camera, the spectrums guided into the spectrum camera are compared to a predetermined reference spectrum and the location of one or more deviations in the analyzed material is defined on the basis of comparison.